



February 18, 2004

To: Commissioner for Patents
P.O.Box 1450
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572
28 Davis Avenue
Poughkeepsie, N.Y. 12603

Subject: | Serial No. 10/719,721 11/21/03 |

Wen-Chi Chien

DYNAMICALLY ADJUSTING THE DISTRIBUTION FOR DISPATCHING LOT BETWEEN CURRENT AND DOWNSTREAM TOOL BY USING EXPERTISE WEIGHTING MECHANISM

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.

The following Patents and/or Publications are submitted to comply with the duty of disclosure under CFR 1.97-1.99 and 37 CFR 1.56.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on February 23, 2004.

Stephen B. Ackerman, Reg.# 37761

Signature/Date

"Understanding the Fundamentals of Kanban and Conwip Pull Systems Using Simulation," Marek, et al., Proceedings of the 2001 Winter Simulation Conference, pp. 921-929, found on website www.informs-cs.org, 6/12/03. This paper presents an introductory overview and tutorial in simulation modeling and control of serial Kanban and CONWIP (CONstant Work In Process) pull systems using AREENA/SIMAN 3.5/4.0.

U.S. Patent 6,564,113 to Barto et al., "Lot Start Agent that Calculates Virtual Wip Time in a Multi-product and Multi-bottleneck Manufacturing Environment," describes a Lot start agent that calculates virtual WIP time in a multi-product and multi-bottleneck manufacturing environment.

U.S. Patent 6,470,227 to Rangachari et al., "Method and Apparatus for Automating a Microelectric Manufacturing Process," describes a method and the apparatus for automating a microelectric manufacturing process by configuring application objects that implement a domain knowledge for a piece of equipment and then implementing a workflow.

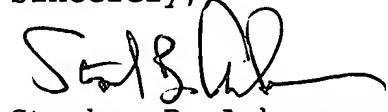
U.S. Patent 6,259,959 to Martin, "Method for Determining the Performance Components of a Manufacturing Line," describes a method for determining the performance components of a manufacturing line.

U.S. Patent 6,128,588 to Chacon, "Integrated Wafer FAB Time Standard (Machine Tact) Database," describes an integrated wafer fab time standard (machine tact) database.

U.S. Patent 5,826,238 to Chen et al., "Daily Target Generation and Machine Allocation with Priority," describes a method and system that operates a data processing system.

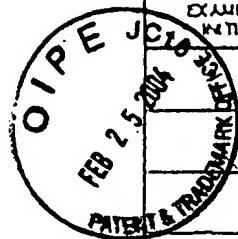
U.S. Patent 5,768,133 to Chen et al., "WIP/Move Management Tool for Semiconductor Manufacturing Plant and Method of Operation Thereof," describes a WIP/move management tool for semiconductor manufacturing plant and method of operation thereof.

Sincerely,



Stephen B. Ackerman,
Reg. No. 37761

Form PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION <i>(Use several sheets if necessary)</i>	Document Number (Specified) TSMC-02-1147	Application Number 101719,721
	Applicant Wen-Chi Chien	
	Filing Date 11/21/03	Group Art Unit



U. S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

OTHER DOCUMENTS (Including Author, Title, Date, Portion or Pages, Etc.)

- "Understanding the Fundamentals of Kanban and Conway's Pull Systems Using Simulation," Marek, et al., Proceedings of the 2001 Winter Simulation Conf., pp. 921-929, found on the website www.informs.cs.org, 6/12/03.

ВАШИ

~~DATE CONSIDERED~~

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.